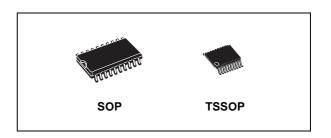


# OCTAL D-TYPE FLIP FLOP WITH CLEAR

- HIGH SPEED: f<sub>MAX</sub> = 165 MHz (TYP.) at V<sub>CC</sub> = 5V
- LOW POWER DISSIPATION:  $I_{CC} = 4 \mu A \text{ (MAX.)}$  at  $T_A=25^{\circ}\text{C}$
- HIGH NOISE IMMUNITY: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (MIN.)
- POWER DOWN PROTECTION ON INPUTS
- SYMMETRICAL OUTPUT IMPEDANCE: |I<sub>OH</sub>| = I<sub>OL</sub> = 8 mA (MIN)
- BALANCED PROPAGATION DELAYS: t<sub>PLH</sub> ≅ t<sub>PHL</sub>
- OPERATING VOLTAGE RANGE: V<sub>CC</sub>(OPR) = 2V to 5.5V
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 273
- IMPROVED LATCH-UP IMMUNITY
- LOW NOISE: V<sub>OLP</sub> = 0.9V (MAX.)



The 74VHC273 is an advanced high-speed CMOS OCTAL D-TYPE FLIP FLOP WITH CLEAR fabricated with sub-micron silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology. Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse.



#### **ORDER CODES**

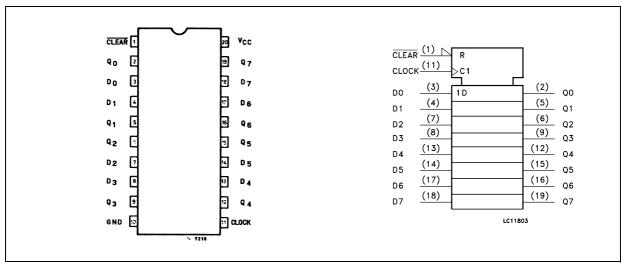
PACKAGE	TUBE	T & R
SOP	74VHC273M	74VHC273MTR
TSSOP		74VHC273TTR

When the CLEAR input is held low, the Q outputs are held low independently of the other inputs.

Power down protection is provided on all inputs and 0 to 7V can be accepted on inputs with no regard to the supply voltage. This device can be used to interface 5V to 3V.

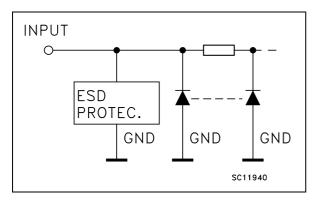
All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

#### PIN CONNECTION AND IEC LOGIC SYMBOLS



June 2001 1/11

## **INPUT EQUIVALENT CIRCUIT**



### **PIN DESCRIPTION**

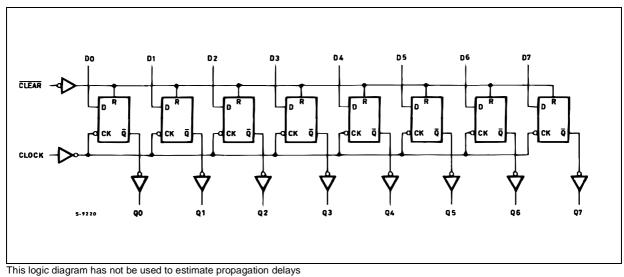
PIN No	SYMBOL	NAME AND FUNCTION
1	CLEAR	Asynchronous Master Reset (Active LOW)
2, 5, 6, 9, 12, 15, 16,19	Q0 to Q7	Flip-Flop Outputs
3, 4, 7, 8, 13, 14, 17, 18	D0 to D7	Data Inputs
11	CLOCK	Clock Input (LOW-to-HIGH Edge Triggered)
10	GND	Ground (0V)
20	V <sub>CC</sub>	Positive Supply Voltage

### **TRUTH TABLE**

	INPUTS		OUTPUT	FUNCTION	
CLEAR	D	В	Q	FUNCTION	
L	X	Х	L	CLEAR	
Н	L		L		
Н	Н		Н		
Н	X	7	Q <sub>n</sub>	NO CHANGE	

X : Don't Care

## **LOGIC DIAGRAM**



## **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	-0.5 to +7.0	V
V <sub>I</sub>	DC Input Voltage	-0.5 to +7.0	V
Vo	DC Output Voltage	-0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	DC Input Diode Current	- 20	mA
I <sub>OK</sub>	DC Output Diode Current	± 20	mA
Io	DC Output Current	± 25	mA
I <sub>CC</sub> or I <sub>GND</sub>	DC V <sub>CC</sub> or Ground Current	± 75	mA
T <sub>stg</sub>	Storage Temperature	-65 to +150	°C
TL	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied

### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	2 to 5.5	V
V <sub>I</sub>	Input Voltage	0 to 5.5	V
Vo	Output Voltage	0 to V <sub>CC</sub>	V
T <sub>op</sub>	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time (note 1) ( $V_{CC}$ = 3.3 $\pm$ 0.3V) ( $V_{CC}$ = 5.0 $\pm$ 0.5V)	0 to 100 0 to 20	ns/V

<sup>1)</sup>  $V_{IN}$  from 30% to 70% of  $V_{CC}$ 

## **DC SPECIFICATIONS**

		7	Test Condition	Value							
Symbol	Parameter	v <sub>cc</sub>	Vcc		T <sub>A</sub> = 25°C -40 to			o 85°C   -55 to 125			Unit
		(V)		Min.	Тур.	Max.	Min.	Max.	Min.	Max.	
V <sub>IH</sub>	High Level Input	2.0		1.5			1.5		1.5		
	Voltage	3.0 to 5.5		0.7V <sub>CC</sub>			0.7V <sub>CC</sub>		0.7V <sub>CC</sub>		V
V <sub>IL</sub>	Low Level Input	2.0				0.5		0.5		0.5	
	Voltage	3.0 to 5.5				0.3V <sub>CC</sub>		0.3V <sub>CC</sub>		0.3V <sub>CC</sub>	V
V <sub>OH</sub>	High Level Output	2.0	I <sub>O</sub> =-50 μA	1.9	2.0		1.9		1.9		
	Voltage	3.0	I <sub>O</sub> =-50 μA	2.9	3.0		2.9		2.9		
		4.5	I <sub>O</sub> =-50 μA	4.4	4.5		4.4		4.4		V
		3.0	I <sub>O</sub> =-4 mA	2.58			2.48		2.4		
		4.5	I <sub>O</sub> =-8 mA	3.94			3.8		3.7		
V <sub>OL</sub>	Low Level Output	2.0	I <sub>O</sub> =50 μA		0.0	0.1		0.1		0.1	
	Voltage	3.0	I <sub>O</sub> =50 μA		0.0	0.1		0.1		0.1	
		4.5	I <sub>O</sub> =50 μA		0.0	0.1		0.1		0.1	V
		3.0	I <sub>O</sub> =4 mA			0.36		0.44		0.55	
		4.5	I <sub>O</sub> =8 mA			0.36		0.44		0.55	
I <sub>I</sub>	Input Leakage Current	0 to 5.5	V <sub>I</sub> = 5.5V or GND			± 0.1		± 1		± 1	μΑ
I <sub>CC</sub>	Quiescent Supply Current	5.5	$V_I = V_{CC}$ or GND			4		40		40	μΑ

# AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3ns$ )

		Т	est Co	ndition	Value							
Symbol	Parameter	v <sub>cc</sub>	CL		Т	A = 25°	С	-40 to 85°C		-55 to 125°C		Unit
		(V)	(pF)		Min.	Тур.	Max.	Min.	Max.	Min.	Max.	
t <sub>PLH</sub>	Propagation Delay	3.3 <sup>(*)</sup>	15			8.7	13.6	1.0	16.0	1.0	16.0	
t <sub>PHL</sub>	Time CLOCK to Q	3.3 <sup>(*)</sup>	50			11.2	17.1	1.0	19.5	1.0	19.5	nc
	02001110 4	5.0 <sup>(**)</sup>	15			5.8	9.0	1.0	10.5	1.0	10.5	ns
		5.0 <sup>(**)</sup>	50			7.3	11.0	1.0	12.5	1.0	12.5	
t <sub>PHL</sub>	Propagation Delay	3.3 <sup>(*)</sup>	15			8.9	13.6	1.0	16.0	1.0	16.0	
	Time CLEAR to Q	3.3 <sup>(*)</sup>	50			11.4	17.1	1.0	19.5	1.0	19.5	
	CLLAN IO Q	5.0 <sup>(**)</sup>	15			5.2	8.5	1.0	10.0	1.0	10.0	ns
		5.0 <sup>(**)</sup>	50			6.7	10.5	1.0	12.0	1.0	12.0	
t <sub>W</sub>	CLEAR Pulse Width LOW	3.3 <sup>(*)</sup>					5.0		6.0		6.0	20
		5.0 <sup>(**)</sup>					5.0		5.0		5.0	ns
t <sub>W</sub>	CLOCK Pulse	3.3 <sup>(*)</sup>					5.5		6.5		6.5	
	Width HIGH or LOW	5.0(**)					5.0		5.0		5.0	ns
t <sub>s</sub>	Setup Time D to	3.3 <sup>(*)</sup>					5.5		6.5		6.5	
	CLOCK, HIGH or LOW	5.0(**)					4.5		4.5		4.5	ns
t <sub>h</sub>	Hold Time D to	3.3 <sup>(*)</sup>					1.0		1.0		1.0	
	CLOCK, HIGH or LOW	5.0 <sup>(**)</sup>					1.0		1.0		1.0	ns
t <sub>REM</sub>	Removal Time	3.3 <sup>(*)</sup>					2.5		2.5		2.5	
	CLEAR to CLOCK	5.0(**)					2.0		2.0		2.0	ns
f <sub>MAX</sub>	Maximum Clock	3.3 <sup>(*)</sup>	15		75	120		65		65		
	Frequency	3.3 <sup>(*)</sup>	50		50	75		45		45		NAL I-
		5.0 <sup>(**)</sup>	15		120	165		100		100		MHz
		5.0 <sup>(**)</sup>	50		80	110		70		70		
t <sub>OSLH</sub>	Output to Output	3.3 <sup>(*)</sup>	50				1.5		1.5		1.5	nc
toshl	Skew time (note 1)	5.0 <sup>(**)</sup>	50				1.0		1.0		1.0	ns

(\*) Voltage range is  $3.3 \text{V} \pm 0.3 \text{V}$  (\*\*) Voltage range is  $5.0 \text{V} \pm 0.5 \text{V}$  Note 1 : Parameter guaranteed by design.  $t_{\text{SoLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|$ ,  $t_{\text{soHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|$ 

### **CAPACITIVE CHARACTERISTICS**

		Test Condition		Value						
Symbol	Parameter		T <sub>A</sub> = 25°C			-40 to 85°C		-55 to 125°C		Unit
			Min.	Тур.	Max.	Min.	Max.	Min.	Max.	
C <sub>IN</sub>	Input Capacitance			7	10		10		10	pF
C <sub>PD</sub>	Power Dissipation Capacitance (note 1)			31						pF

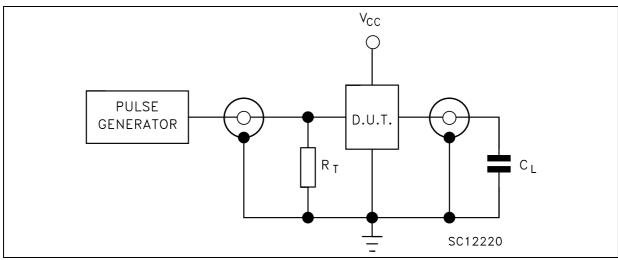
<sup>1)</sup>  $C_{PD}$  is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation.  $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8$  (per Flip-Flop)



### **DYNAMIC SWITCHING CHARACTERISTICS**

			Test Condition		Value						
Symbol	Parameter	v <sub>cc</sub>		Т	$T_A = 25^{\circ}C$		-40 to 85°C		-55 to	125°C	Unit
	(V)		Min.	Тур.	Max.	Min.	Max.	Min.	Max.		
V <sub>OLP</sub>	Dynamic Low	5.0			0.6	0.9					.,
V <sub>OLV</sub>	Voltage Quiet Output (note 1, 2)		C <sub>L</sub> = 50 pF	-0.9	-0.6						V
V <sub>IHD</sub>	Dynamic High Voltage Input (note 1, 3)	5.0		3.5							V
V <sub>ILD</sub>	Dynamic Low Voltage Input (note 1, 3)	5.0				1.5					V

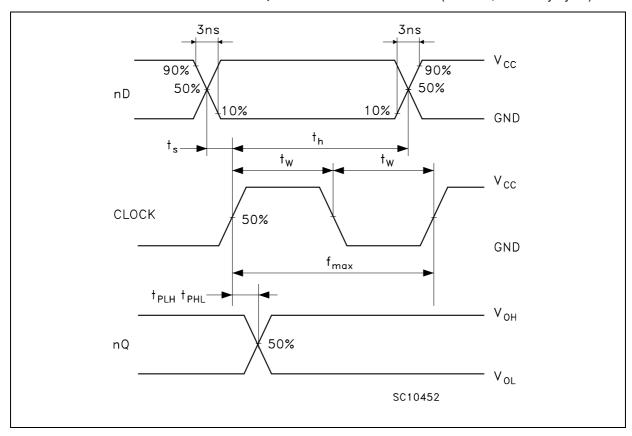
## **TEST CIRCUIT**



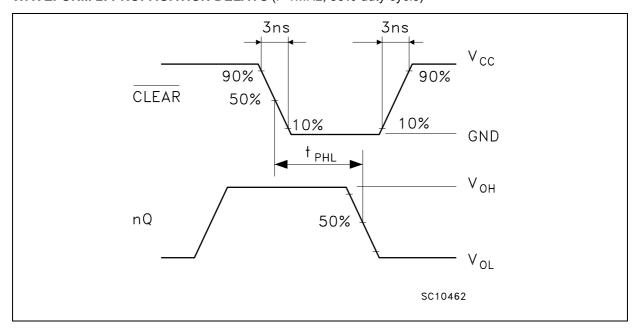
 $C_L$  =15/50pF or equivalent (includes jig and probe capacitance)  $R_T$  =  $Z_{OUT}$  of pulse generator (typically 50 $\Omega$ )

<sup>1)</sup> Worst case package.
2) Max number of outputs defined as (n). Data inputs are driven 0V to 5.0V, (n-1) outputs switching and one output at GND.
3) Max number of data inputs (n) switching. (n-1) switching 0V to 5.0V. Inputs under test switching: 5.0V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>), f=1MHz.

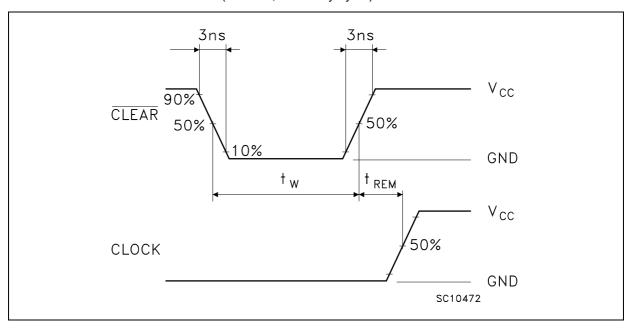
## WAVEFORM 1: PROPAGATION DELAYS, SETUP AND HOLD TIMES (f=1MHz; 50% duty cycle)



# WAVEFORM 2: PROPAGATION DELAYS (f=1MHz; 50% duty cycle)

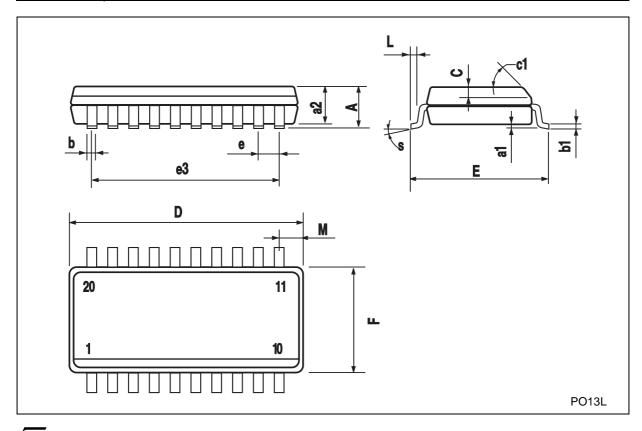


# WAVEFORM 3: RECOVERY TIME (f=1MHz; 50% duty cycle)



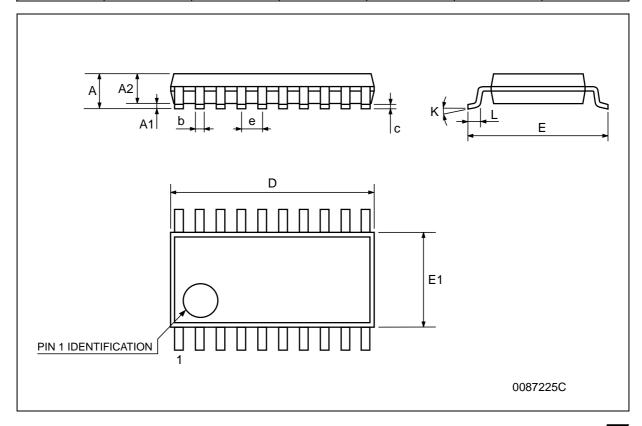
# **SO-20 MECHANICAL DATA**

DIM		mm.		inch				
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.		
А			2.65			0.104		
a1	0.1		0.2	0.004		0.008		
a2			2.45			0.096		
b	0.35		0.49	0.014		0.019		
b1	0.23		0.32	0.009		0.012		
С		0.5			0.020			
c1			45°	(typ.)				
D	12.60		13.00	0.496		0.512		
E	10.00		10.65	0.393		0.419		
е		1.27			0.050			
e3		11.43			0.450			
F	7.40		7.60	0.291		0.300		
L	0.50		1.27	0.020		0.050		
М			0.75			0.029		
S			8° (r	max.)		•		



# **TSSOP20 MECHANICAL DATA**

DIM.		mm.		inch				
DIW.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.		
А			1.2			0.047		
A1	0.05		0.15	0.002	0.004	0.006		
A2	0.8	1	1.05	0.031	0.039	0.041		
b	0.19		0.30	0.007		0.012		
С	0.09		0.20	0.004		0.0089		
D	6.4	6.5	6.6	0.252	0.256	0.260		
E	6.2	6.4	6.6	0.244	0.252	0.260		
E1	4.3	4.4	4.48	0.169	0.173	0.176		
е		0.65 BSC			0.0256 BSC			
K	0°		8°	0°		8°		
L	0.45	0.60	0.75	0.018	0.024	0.030		



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